

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Claim 1 (currently amended): A measuring system (1) for detecting defects of an object (2) having at least a first (2a) and a second (2b) layer, which system (1) comprises at least one light source (3) arranged to illuminate the object (2) with incident light (4), an imaging sensor (6) arranged to detect reflected light (5b) from the object (2) and to convert the detected light into electrical charges and, means for creating a representation of the object (2) according to the electrical charges, ~~characterised in that~~ wherein the system (1) comprises means for obtaining information on light scattered (5a) in the first layer (2a) and the second layer (2b) of the object (2) from the representation and, means for comparing the information to stored information in order to detect defects on the object (2).

Claim 2 (currently amended): A measuring system according to claim 1, ~~characterised in that~~ wherein the measuring system (1) and/or the object (2) is/are arranged to move in relation to one another in a predefined direction of movement.

Claim 3 (currently amended): A measuring system according to claim 1, ~~characterised in that~~ wherein the incident light (4) is arranged to have limited dispersion in a predefined direction.

Claim 4 (currently amended): A measuring system according to claim 3, ~~characterised in that~~ wherein the incident light (4) is a linear light.

Claim 5 (currently amended): A measuring system according to claim 1, ~~characterised in that~~ wherein the system further comprises means for obtaining information on the geometric profile of the object (2) from the representation.

Claim 6 (currently amended): A measuring system according to claim 5, ~~characterised in that~~ wherein the system comprises means for obtaining information on the geometric profile of the first layer (2a) of the object (2) from the representation.

Claim 7 (currently amended): A measuring system according to claim 5, ~~characterised in that~~ wherein the system comprises means for obtaining information on the geometric profile of the second layer (2b) of the object (2) from the representation.

Claim 8 (currently amended): A measuring system according to claim 1, ~~characterised in that~~ wherein the light source (3) comprises a polarizer arranged to facilitate the distinction between light reflected on the object (2) and scattered light in the object (2).

Claim 9 (currently amended): A measuring system according to claim 1, ~~characterised in that~~ wherein the first layer (2a) consist of a transparent or semi-transparent material.

Claim 10 (currently amended): A measuring system according to claim 1, ~~characterised in that~~ wherein the object (2) is a package wrapped in a protective material.

Claim 11 (currently amended): A method for detecting defects of an object having at least a first and a second layer by means of a measuring system, in which method the object is illuminated by means of incident light, and light reflected from the object is detected by means of an imaging sensor in which the detected light is converted into electrical charges, according to which a representation of the object is created, ~~characterised in that~~ wherein information on light scattered in the first layer and the second layer of the object is obtained from the representation and ~~that~~ wherein the information is compared to stored information in order to detect defects on the object.

Claim 12 (currently amended): A method according to claim 11, ~~characterised in that~~ wherein the measuring system and/or the object is/are moved in relation to one another in a predefined direction of movement.

Claim 13 (currently amended): A method according to claim 11, ~~characterised in that~~ wherein also information on the geometric profile of the object is obtained from the representation.

Claim 14 (currently amended): A method according to claim 13, ~~characterised in that~~ wherein information on the geometric profile of the first layer of the object is obtained from the representation.

Claim 15 (currently amended): A method according to claim 13, ~~characterised in that~~ wherein information on the geometric profile of the second layer of the object is obtained from the representation.

Claim 16 (currently amended): A method according to claim 11, ~~characterised in that~~ wherein the incident light is polarized and ~~that~~ wherein the polarized incident light is used to distinguish between reflected light on the object and scattered light in the object.